Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/044,008	JAIN ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

SEARCHED						
Class	Subclass	Date	Examiner			
713	180, 168	3/8/2006	S.C.			
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
			-			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
DATE	EXMR				
/8/2006	S.C.				